

Monolithic Active Pixel Sensor R&D in 65 nm for

high-resolution, minimal-mass, wafer-scale, bent tracking detectors

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Magnus Mager (CERN) on behalf of the ALICE collaboration



Outline

- Starting point: ALICE ITS2
 - short review of the detector
 - motivation to go further

- ALICE ITS3 (target: LHC LS3)
 - detector and project overview
 - sensor development in 65 nm
 - beam tests with bent MAPS

















ALICE Detector and main goals





Study of QGP in heavy-ion collisions at LHC

- i.e. up to O(10k) particles to be tracked in a single event
- Reconstruction of charm and beauty hadrons
- Interest in low momentum (\$1 GeV/c) particle reconstruction









ALICE today LS2 upgrades with Monolithic Active Pixel Sensors (MAPS)





Inner Tracking System

LS2

6 layers:

2 hybrid silicon pixel

- 2 silicon drift
- 2 silicon strip

Inner-most layer:

radial distance: 39 mm material: $X/X_0 = 1.14\%$ pitch: $50 \times 425 \ \mu m^2$ rate capability: 1 kHz

7 layers: all MAPS

Inner-most layer:

radial distance: 23 mm material: $X/X_0 = 0.3\%$ pitch: $O(30 \times 30 \ \mu m^2)$ rate capability: 100 kHz (Pb-Pb)

Muon Forward Tracker

new detector

5 discs, double sided: based on same technology as ITS2















Good news: it was all built, assembled and tested!

ITS2 inner barrel



- ITS2 will already have unprecedented performance



ITS2: assembled three inner-most half-layers



• The Inner Barrel is ultra-light but rather packed \rightarrow further improvements seem possible

Key questions: Can we get closer to the IP? Can we reduce the material further?







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ITS3 detector concept



Beam pipe Inner/Outer Radius (mm)		16.0/16.5	
IB Layer Parameters	Layer 0	Layer 1	Layer 2
Radial position (mm)	18.0	24.0	30.0
Length (sensitive area) (mm)	300		
Pseudo-rapidity coverage	±2.5	±2.3	±2.0
Active area (cm ²)	610	816	1016
Pixel sensor dimensions (mm ²)	280 x 56.5	280 x 75.5	280 x 94
Number of sensors per layer	2		
Pixel size (µm²)	O (10 x 10)		



	Key	ingred	ients:
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- 300 mm wafer-scale chips, fabricated using stitching
- thinned down to 20-40 µm (0.02-0.04%) X0), making them flexible
- bent to the target radii
- mechanically held in place by carbon foam ribs
- Key benefits:
 - extremely low material budget: 0.02-0.04% X0
 - (beampipe: 500 µm Be: 0.14% X0)
 - homogeneous material distribution: negligible systematic error from material distribution

The whole detector will comprise six (!) chips – and barely anything else



















ITS3 performance figures

pointing resolution



[ALICE-PUBLIC-2018-013]

improvement of factor 2 over all momenta



tracking efficiency



large improvement for low transverse momenta







ITS3 project startup Eol, Lol, start of R&D



[LHCC minutes: <u>CERN-LHCC-2019-010 ; LHCC-139</u>]









ITS3 timeline main milestones



MLR: multiple layer per reticle, **ER:** engineering run,

BM: breadboard module, EM: engineering module, QM: qualification module, FM: final module





65 nm



Magnus Mager (CERN) | MAPS R&D in 65 nm | LCWS2021 | 18.03.2021 | 13



Sensor challenges and mapping to 65 nm

- Low power consumption (< 20 mW/cm²) inside pixel matrix to allow for air-cooling
- Stitching to obtain wafer-scale sensors
 - 300 mm wafer process to reach z-coverage
- Thinning to < 50 μm to become bendable</p>

while keeping other parameters (high) spatial resolution, moderate radiation hardness, ...) as for ITS2 (ALPIDE)







radiation hardness to be checked charge-collection to be checked/ optimised

Switching from 180 nm (ALPIDE) to 65 nm seems like a perfect fit!





Wafer-scale chip

- Chip size is traditionally limited by CMOS manufacturing ("reticle size")
 - typical sizes of few cm²
 - modules are tiled with chips connected to a flexible printed circuit board









FPC + chips



Wafer-scale chip

- Chip size is traditionally limited by CMOS manufacturing ("reticle size")
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 - modules are tiled with chips connected to a flexible printed circuit board
- New option: stitching, i.e. aligned exposures of a reticle to produce larger circuits
 - actively used in industry
 - a 300 mm wafer can house a chip to equip a full half-layer
 - requires dedicated chip design







Wafer-scale sensor



Sensor dimensions 65 nm process

- All the three foreseen (half-) layers can be equipped with a single chip of a 300 mm wafer
- This is the driving argument for ITS3 to go to the 65 nm process
- At the same time, ITS3 wants to exploit the technology at its best, potentially:
 - lower power
 - more logic
 - smaller pixels
 - faster readout







Architecture Ideas + Challenges

- Stitching requires a regular, periodic structure of the matrix
- Different architectures are under study
 - here, the concept laid out in the Lol is mostly inspired by ALPIDE
- ITS3 needs three different chip sizes
 - naturally comes with stitching a variable number of "rows"
 - likely adaptable to other geometries (e.g. square-like matrices)
- Electrical interface only on one side
- Power consumption needs to stay low in the matrix region, but can be larger at periphery
 - dictated by air cooling capabilities and acceptable voltage drop along the sensor





Sensor prototyping First 65nm submission "MLR1"

- ITS3 plays a leading role in the evaluation of the TowerJazz 65 nm technology for MAPS
- First test structures in 65 nm have been just submitted
 - transistor test structures for radiation hardness studies
 - various diode matrices for charge-collection studies
 - analog building blocks
- Large number of dies in different processing flavours are expected
 - will provide crucial input into the next design steps
- Wafer-scale blocks will be diced out to study mechanical properties
- First chips expected mid 2021: stay tuned!





expect O(500) dies per wafer



Bent MAPS







Bending ALP DE example

tension wire

17700

100 µm-thick Kapton

off the second s

50 µm-thick ALPIDE

R = 18 mm jig



Bending of wafer-scale chips first test with dummy silicon



Mylar foil

1.1

50 µm-thick dummy silicon, full inner-layer size

R = 30 mm mandrell





Mechanics demonstrator

- Layers can be held in shape and position with a minimal amount of material
- A very light carbon foam is already sufficient
- Detailed mechanical and thermal characterisation ongoing





Test beams overview

- 3 beam tests at DESY in 2020
- different DUTs

a) Jun 2020

ec 2020

b) Aug/D

PIDE

comprehensive data set









Example event





ALPIDE bent to R = 18 mm

- beam crossing sensor twice
- shallow incident angles



Example event closeup



first crossing



Test beams 1st paper (draft)



Fig. 10: Inefficiency as a function of threshold for different rows and incident angles with partially logarithmic scale (10^{-1} to 10^{-5}) to show fully efficient rows. Each data point corresponds to at least 8k tracks.





The chips just continue to work!



Summary

- ALICE ITS2 is the first really large-scale (O(10 m²)) application of MAPS in HEP
 - the development of **ALPIDE** marks a **new generation** of MAPS in terms of functionality and performance figures
- ALICE ITS3 will push the technology even further, approaching the massless detector

 - R&D encouraged by LHCC in Sep 2019 and progressing at full steam - 65 nm prototype chips were submitted, expected back mid 2021 - feasibility of curved silicon detectors, marking the start of a new chapter on silicon-detector designs
 - fully integrated, wafer-scale sensors will allow large-scale minimal material budget applications





Thank you!





